Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	150	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	_	0.17	_	V/°C	Reference to 25°C, I _D = 1mA®
R _{DS(on)}	Static Drain-to-Source On-Resistance	_	_	0.042	Ω	V _{GS} = 10V, I _D = 22A ④
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
g _{fs}	Forward Transconductance	19	i		S	V _{DS} = 50V, I _D = 22A⑤
loss	Drain-to-Source Leakage Current	_		25	μА	V _{DS} = 150V, V _{GS} = 0V
		_	_	250		V _{DS} = 120V, V _{GS} = 0V, T _J = 150°C
I _{GSS}	Gate-to-Source Forward Leakage		_	100	nA	V _{GS} = 20V
	Gate-to-Source Reverse Leakage		_	-100		V _{GS} = -20V
Q_g	Total Gate Charge	_	_	200		I _D = 22A
Qgs	Gate-to-Source Charge	-	_	17	nC	V _{DS} = 120V
Q _{gd}	Gate-to-Drain ("Miller") Charge		_	98		V _{GS} = 10V, See Fig. 6 and 13 4 5
t _{d(on)}	Turn-On Delay Time		12			V _{DD} = 75V
tr	RiseTime		55			I _D = 22A
t _{d(off)}	Turn-Off Delay Time		71		ns	$R_G = 2.5\Omega$
t _f	FallTime		69			$R_D = 3.3\Omega$, See Fig. 10 $\textcircled{4}$ $\textcircled{5}$
Ls	Internal Source Inductance		7.5		nH	Between lead, and center of die contact
Ciss	Input Capacitance	_	2400			V _{GS} = 0V
Coss	Output Capacitance	_	640		pF	V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		340	_		f = 1.0MHz, See Fig. 5®

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
k	Continuous Source Current (Body Diode)	_		43		MOSFET symbol showing the integral reverse p-n junction diode.
I _{SM}	Pulsed Source Current (Body Diode) ①⑤	_	-	150	A	
V_{SD}	Diode Forward Voltage			1.3	V	T _J = 25°C, I _S = 22A, V _{GS} = 0V 4
t _{rr}	Reverse Recovery Time		260	390	ns	T _J = 25°C, I _F = 22A
Qrr	Reverse Recovery Charge		2.2	3.3	uС	di/dt = 100A/µs ③ ⑤
ton	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- 4 Pulse width \leq 300 μ s; duty cycle \leq 2%.
- ② Starting $T_J = 25$ °C, L = 2.4mH $R_G = 25\Omega$, $I_{AS} = 22$ A. (See Figure 12)
- ⑤ Uses IRF3415 data and test conditions
- ** When mounted on 1" square PCB (FR-4 or G-10 Material).
 For recommended soldering techniques refer to application note #AN-994.

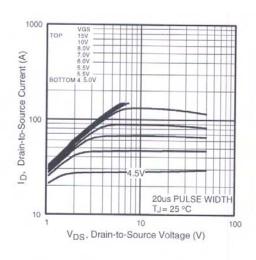


Fig 1. Typical Output Characteristics

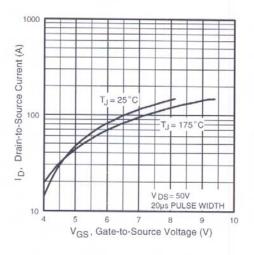


Fig 3. Typical Transfer Characteristics

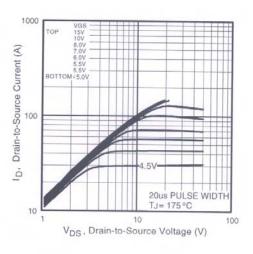


Fig 2. Typical Output Characteristics

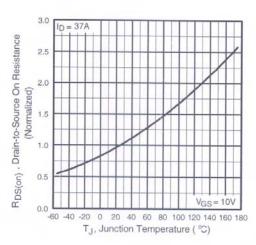


Fig 4. Normalized On-Resistance Vs. Temperature

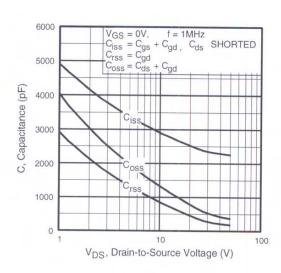


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

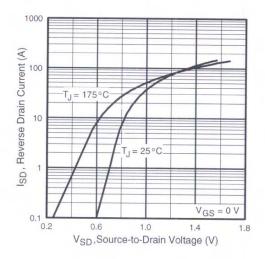


Fig 7. Typical Source-Drain Diode Forward Voltage

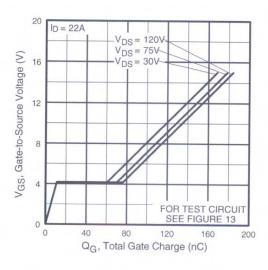


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

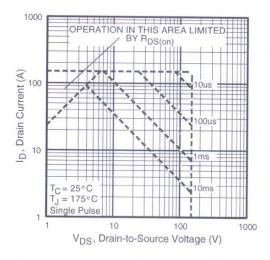


Fig 8. Maximum Safe Operating Area

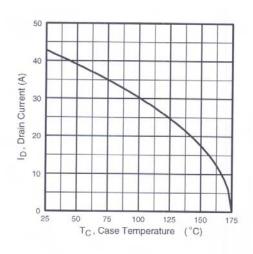


Fig 9. Maximum Drain Current Vs. Case Temperature

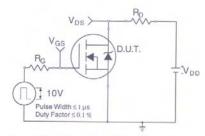


Fig 10a. Switching Time Test Circuit

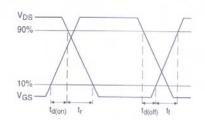


Fig 10b. Switching Time Waveforms

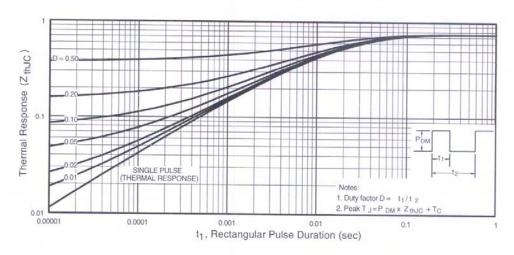


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

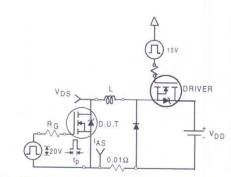


Fig 12a. Unclamped Inductive Test Circuit

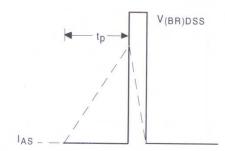


Fig 12b. Unclamped Inductive Waveforms

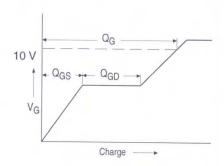


Fig 13a. Basic Gate Charge Waveform

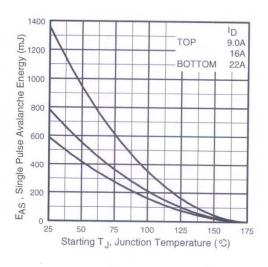


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

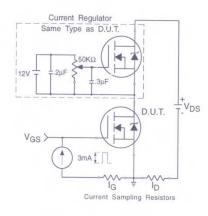
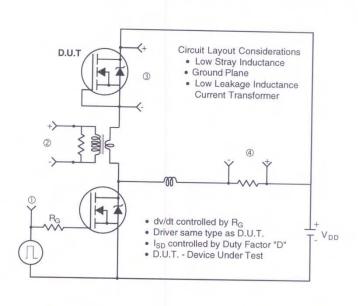


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



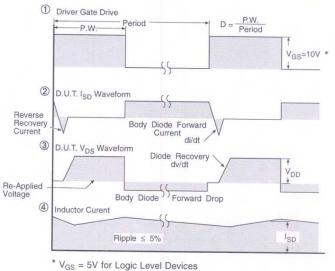
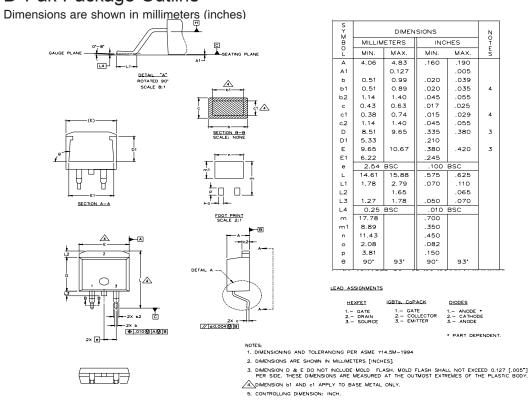


Fig 14. For N-Channel HEXFETS

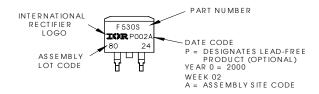
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D²Pak Package Outline

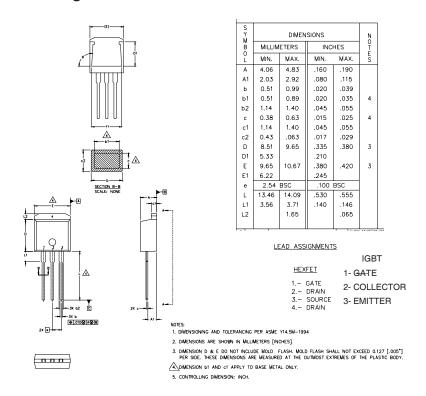


D²Pak Part Marking Information (Lead-Free)

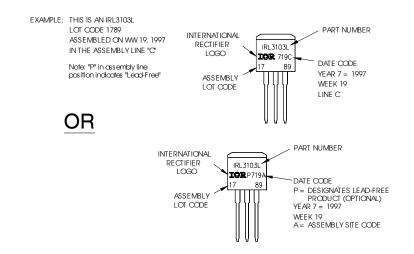




TO-262 Package Outline

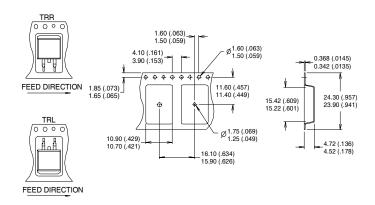


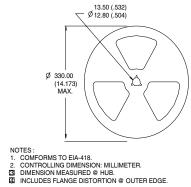
TO-262 Part Marking Information

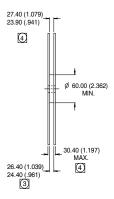


D²Pak Tape & Reel Infomation

Dimensions are shown in millimeters (inches)







Data and specifications subject to change without notice.

International IOR Rectifier

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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/

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